

INFORMATION DISCLOSURE CITATION

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#3

ATTY DOCKET NO.

2002US304

SERIAL NO.

10/042,878

Neisser et al

FILING

01/09/2002

GROUP

1756

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
mb	4,557,797	12/10/1985	Fuller et al	438	514	
	4,863,827	09/05/1989	Jain et al	430	145	
	4,910,127	03/20/1990	Arnold et al	430	313	
	5,635,333	06/03/1997	Peterson et al	430	311	
	5,652,297	07/29/1997	McCulloch et al	524	555	
	5,886,102	03/23/1999	Sinta et al	525	15	
	5,939,236	08/17/1999	Pavelcheck et al	430	271.1	
	5,981,145	11/09/1999	Ding et al	430	271.1	
	6,042,990	03/28/2000	Shao et al	430	271.1	
	6,080,530	06/27/2000	Shao et al	430	325	
mb	6,110,653	08/29/2000	Holmes et al	430	325	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
mb	GB 2 135 793 A	09/05/1984	UK				
	GB 2 357 509	06/27/2001	UK				
	EP 0 542 008 A1	05/19/1993	Europe				
mb	EP 0 813 114 A2	05/28/1997	Europe				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

mb	James Fahey et al, "Design of a Bottom Anti-Reflective Layer for Optical Lithography", SPIE, Vol. 2195, pages 422 - 446
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EXAMINER

Michael R. ...

DATE CONSIDERED

4/24/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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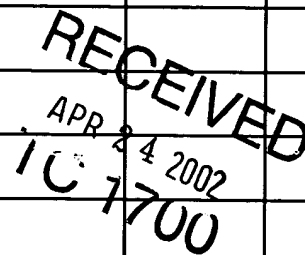
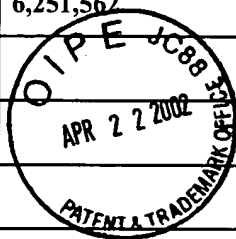
01/09/2002

GROUP

1756

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
W17	6,114,085	09/05/2000	Padmanaban et al	430	270.1	
	6,187,506	02/13/2001	Ding et al	430	271.1	
	6,242,161	06/05/2001	Kawaguchi et al	430	313	
W17	6,251,562	06/26/2001	Breyta et al	430	287.1	



FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

W17		C. Nolscher et al, "High contrast single layer resists and antireflection layers - an alternative to multilayer resist techniques", SPIE, Vol. 1086, 1989, pages 242 - 250

EXAMINER

Michael G. ...

DATE CONSIDERED

6/24/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

2002US36

Application Number

10/042,878

Applicant(s)

Mark O. Neisser et al

Filing Date

January 9, 2002

Group Art Unit

1756

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
nm		6,054,254	04/25/2000	Yasuhiko Sato et al	430	322	
nm		6,261,743 B1	07/17/2001	Pavelcheck et al	430	325	
		6,114,085 A	09/05/2000	Padmanaban et al			
		6,110,653 A	08/29/2000	Steven Holmes et al			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

Mark O. Neisser

DATE CONSIDERED

6/24/03

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INFORMATION DISCLOSURE CITATION

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JUN 02 2003

Docket Number (Optional)

2002US30

Application Number

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Applicant(s)

Mark O. Neisser et al

Filing Date

January 9, 2002

Group Art Unit

1756

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
ny		4,557,996 A	12/10/1985	Toshimi Aoyama et al	430	324	
ny		5,695,910 A	12/09/1997	Fumiyoshi Urano et al	430	270.1	
		5,939,236 A	08/17/1999	Edward K. Pavelcheck et al			
		6,261,743 B1	07/17/2001	Edward K. Pavelchok et al	430	324	
ny		6,319,651 B1	11/20/2001	Steven J. Holmes et al			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
		EP 0 542 008 A	05/19/1993	Europe				
ny		EP 0 726 500 A	08/14/1996	Europe				
		EP 0 813 114 A	12/17/1997	Europe				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

DATE CONSIDERED

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